LEMSYS

QUATEK

LEMSYS SiC Tester for EV and solar module

Dynamic Tester
SLIC-AC 3015

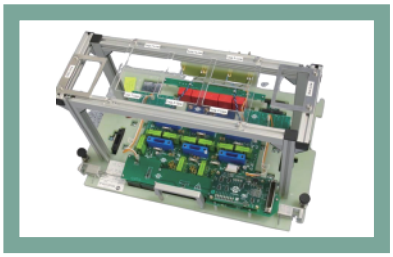
Static Tester
TRs 2030-SLIC

ADAPTED FOR SiC ADAPTED FOR

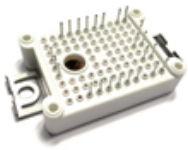
SIC application

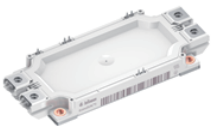
Professional test system for SiC MOSFET and IGBT module
Low stray inductance< 25nH, typical is 20 nH
Difference Ls with 3 phases < 5 nH (typical 2 nH)
AC up to 3000A and 1500V
DC up to 2000A and 3000V
Max Short-circuit current up to 11KA
Fast switch gate control for SiC device
Supply Qg/EAS/SC II/Multi-pulse function
Follow IEC-60747 /AQG-324/JEP-183 standard
Applicable for production as well as R&D investigation
Easy to integrate with the automatic handler

LEMSYS Cclmap Adaptor



Adaptor recognition by software
Gate resistors (0 to 120Ω), software settable
Gate capacitors (0 to 30nF), software settable
Active Clamp on Gate and Collector
Typical apparent stray inductance 20nH (defined between +DC and -DC)
Compatible with kinds of SiC/IGBT module for EV and solar application





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